

## NX3008PBKS

# 30 V, 200 mA dual P-channel Trench MOSFET Rev. 1 — 1 August 2011

**Product data sheet** 

## **Product profile**

## 1.1 General description

Dual P-channel enhancement mode Field-Effect Transistor (FET) in a very small SOT363 (SC-88) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

#### 1.2 Features and benefits

- Very fast switching
- Low threshold voltage
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

### 1.3 Applications

- Relay driver
- High-speed line driver

- High-side loadswitch
- Switching circuits

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Per transistor							
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> = 25 °C		-	-	-30	V
V <sub>GS</sub>	gate-source voltage			-8	-	8	V
I <sub>D</sub>	drain current	$V_{GS} = -4.5 \text{ V};$ $T_{amb} = 25 \text{ °C}$	<u>[1]</u>	-	-	-200	mA
Static characte	eristics (per transistor)						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = -4.5 \text{ V};$ $I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$		-	2.8	4.1	Ω

<sup>[1]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source TR1	D. D. D.	D
2	G1	gate TR1	6 5 4	D1 D2
3	D2	drain TR2		
4	S2	source TR2	0	$G1 \longrightarrow G2$
5	G2	gate TR2	□1 □2 □3	
6	D1	drain TR1	SOT363 (SC-88)	14 23
				S1 S2 017aaa260

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
NX3008PBKS	SC-88	plastic surface-mounted package; 6 leads	SOT363

## 4. Marking

Table 4. Marking codes

Type number	Marking code <sup>[1]</sup>
NX3008PBKS	LC%

<sup>[1]</sup> % = placeholder for manufacturing site code.

## 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
Per transistor						
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> = 25 °C		-	-30	V
$V_{GS}$	gate-source voltage			-8	8	V
I <sub>D</sub>	drain current	$V_{GS} = -4.5 \text{ V}; T_{amb} = 25 \text{ °C}$	[1]	-	-200	mA
		$V_{GS} = -4.5 \text{ V}; T_{amb} = 100 \text{ °C}$	[1]	-	-125	mA
I <sub>DM</sub>	peak drain current	$T_{amb} = 25$ °C; single pulse; $t_p \le 10 \mu s$		-	-0.8	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2]	-	280	mW
			[1]	-	320	mW
		$T_{sp} = 25  ^{\circ}C$		-	990	mW
Per device						
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2]	-	445	mW
Tj	junction temperature			-55	150	°C
T <sub>amb</sub>	ambient temperature			-55	150	°C
T <sub>stg</sub>	storage temperature			-65	150	°C
Source-drain	Source-drain diode					
Is	source current	T <sub>amb</sub> = 25 °C	<u>[1]</u>	-	-200	mA
ESD maximun	n rating					
V <sub>ESD</sub>	electrostatic discharge voltage	НВМ	[3]	-	2000	V

<sup>[1]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.

<sup>[2]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

<sup>[3]</sup> Measured between all pins.

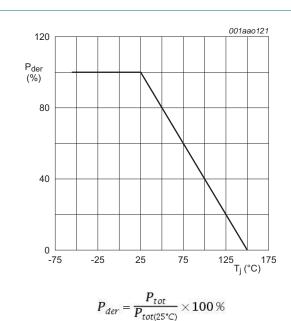


Fig 1. Normalized total power dissipation as a function of junction temperature

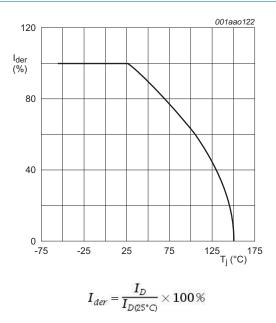
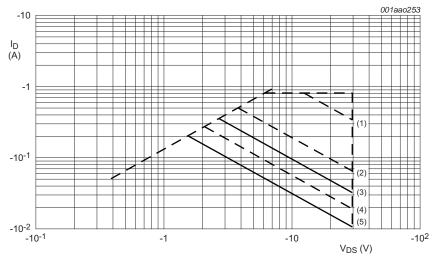


Fig 2. Normalized continuous drain current as a function of junction temperature



I<sub>DM</sub> is a single pulse

(1) 
$$t_p = 1 \text{ ms}$$

(2) 
$$t_p = 10 \text{ ms}$$

(3) DC; 
$$T_{sp} = 25 \, ^{\circ}\text{C}$$

(4) 
$$t_p = 100 \text{ ms}$$

(5) DC;  $T_{amb} = 25 \text{ °C}$ ; 1 cm<sup>2</sup> drain mounting pad

Fig 3. Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

## 6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Per device						
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	-	300	K/W
Per transisto	or					
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	390	445	K/W
			[2] -	340	390	K/W
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point		-	-	130	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm<sup>2</sup>.

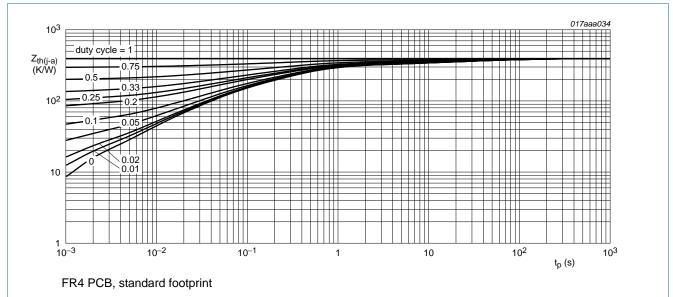


Fig 4. Per transistor: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

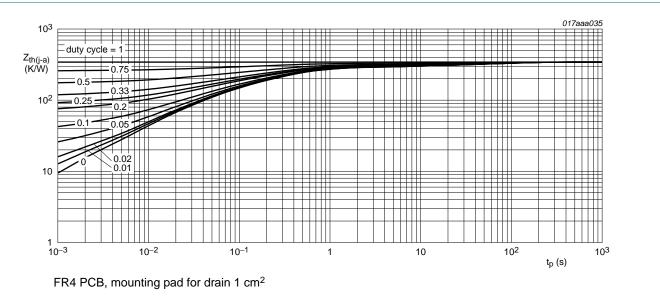


Fig 5. Per transistor: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

## 7. Characteristics

Table 7. Characteristics

	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics (per transistor)					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = -250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	-30	-	-	V
$V_{GSth}$	gate-source threshold voltage	$I_D = -250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	-0.6	-0.9	-1.1	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = -30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	-1	μΑ
		$V_{DS} = -30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	-10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-0.2	-1	μΑ
		$V_{GS}$ = -8 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	-0.2	-1	μΑ
		$V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-10	-	nA
		$V_{GS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-10	-	nA
		$V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-1	-	nA
		$V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-1	-	nA
R <sub>DSon</sub>	drain-source on-state	$V_{GS}$ = -4.5 V; $I_D$ = -200 mA; $T_j$ = 25 °C	-	2.8	4.1	Ω
	resistance	$V_{GS}$ = -4.5 V; $I_D$ = -200 mA; $T_j$ = 150 °C	-	5.3	7.8	Ω
		$V_{GS}$ = -2.5 V; $I_D$ = -10 mA; $T_j$ = 25 °C	-	5.3	6.5	Ω
9 <sub>fs</sub>	forward transconductance	$V_{DS} = -10 \text{ V}; I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$	-	160	-	mS
Dynamic c	haracteristics (per transist	or)				
Q <sub>G(tot)</sub>	total gate charge	$V_{DS} = -15 \text{ V}; I_D = -200 \text{ mA};$	-	0.55	0.72	nC
$Q_{GS}$	gate-source charge	$V_{GS} = -4.5 \text{ V}; T_j = 25 \text{ °C}$	-	0.23	-	nC
$Q_{GD}$	gate-drain charge		-	0.09	-	nC
C <sub>iss</sub>	input capacitance	$V_{DS} = -15 \text{ V; } f = 1 \text{ MHz; } V_{GS} = 0 \text{ V;}$	-	31	46	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C	-	6.5	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	2.3	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = -20 V; $R_L$ = 250 $\Omega$ ; $V_{GS}$ = -4.5 V;	-	19	38	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	30	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	65	130	ns
t <sub>f</sub>	fall time		-	38	-	ns
Source-dra	nin diode (per transistor)					
$V_{SD}$	source-drain voltage	$I_S = -200 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-0.47	-0.88	-1.2	V

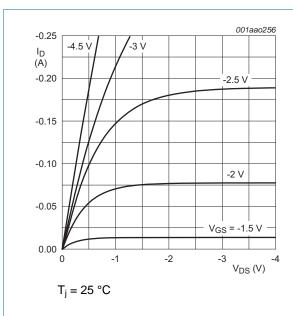
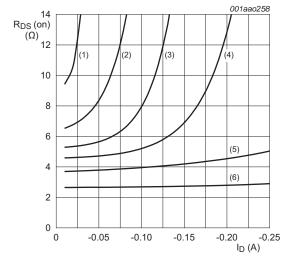


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



T<sub>i</sub> = 25 °C

(1)  $V_{GS} = -1.75 \text{ V}$ 

(2)  $V_{GS} = -2.0 \text{ V}$ 

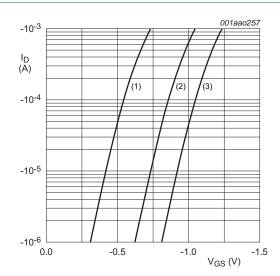
(3)  $V_{GS} = -2.25 \text{ V}$ 

(4)  $V_{GS} = -2.5 \text{ V}$ 

(5)  $V_{GS} = -3.0 \text{ V}$ 

(6)  $V_{GS} = -4.5 \text{ V}$ 

Fig 8. Drain-source on-state resistance as a function of drain current; typical values



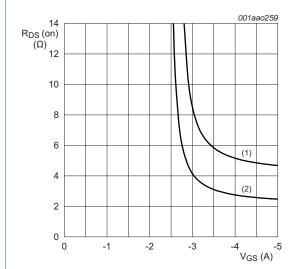
 $T_{j} = 25 \, ^{\circ}\text{C}; \, V_{DS} = -5 \, \text{V}$ 

(1) minimum values

(2) typical values

(3) maximum values

Fig 7. Sub-threshold drain current as a function of gate-source voltage

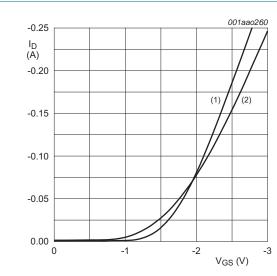


 $I_D = -200 \text{ mA}$ 

(1)  $T_i = 150 \,^{\circ}C$ 

(2)  $T_i = 25 \, ^{\circ}\text{C}$ 

Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values

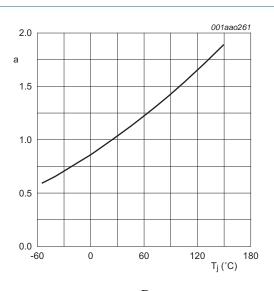


 $V_{DS} > I_D \times R_{DSon}$ 

(1) 
$$T_j = 25 \, ^{\circ}C$$

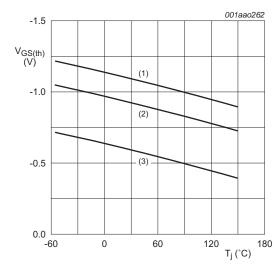
(2) 
$$T_i = 150 \, ^{\circ}\text{C}$$

Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

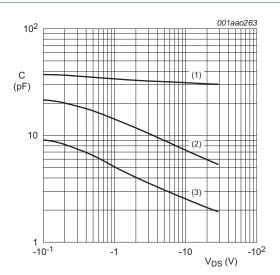
Fig 11. Normalized drain-source on-state resistance as a function of junction temperature; typical values



 $I_D$  = -0.25 mA;  $V_{DS}$  =  $V_{GS}$ 

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 12. Gate-source threshold voltage as a function of junction temperature



 $f = 1 MHz; V_{GS} = 0 V$ 

(1)C<sub>iss</sub>

(2)C<sub>oss</sub>

(3)C<sub>rss</sub>

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

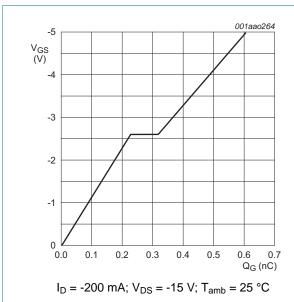


Fig 14. Gate-source voltage as a function of gate charge; typical values

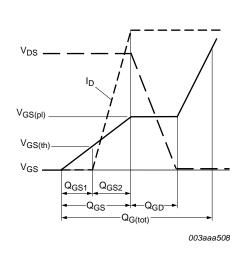
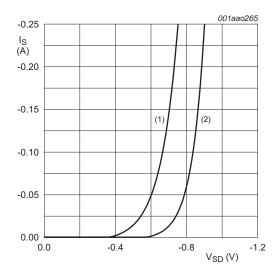


Fig 15. Gate charge waveform definitions



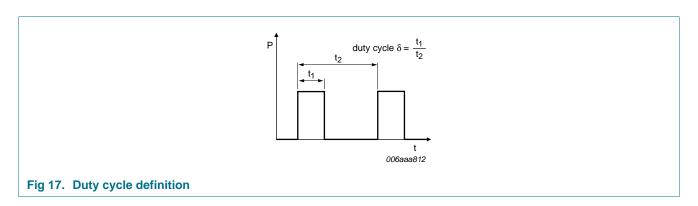
 $V_{GS} = 0 V$ 

(1)  $T_i = 150 \, ^{\circ}\text{C}$ 

(2)  $T_j = 25 \, ^{\circ}C$ 

Fig 16. Source current as a function of source-drain voltage; typical values

## 8. Test information



## 8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

## 9. Package outline

## Plastic surface-mounted package; 6 leads

**SOT363** 

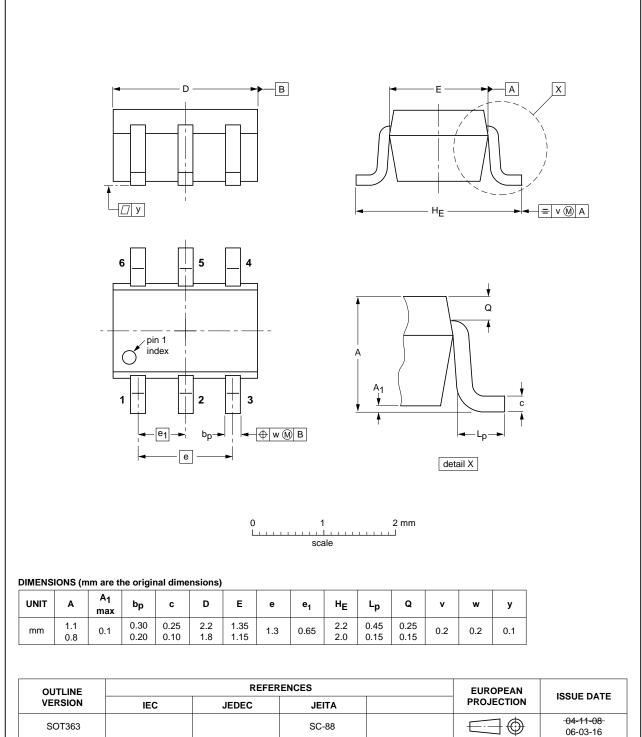


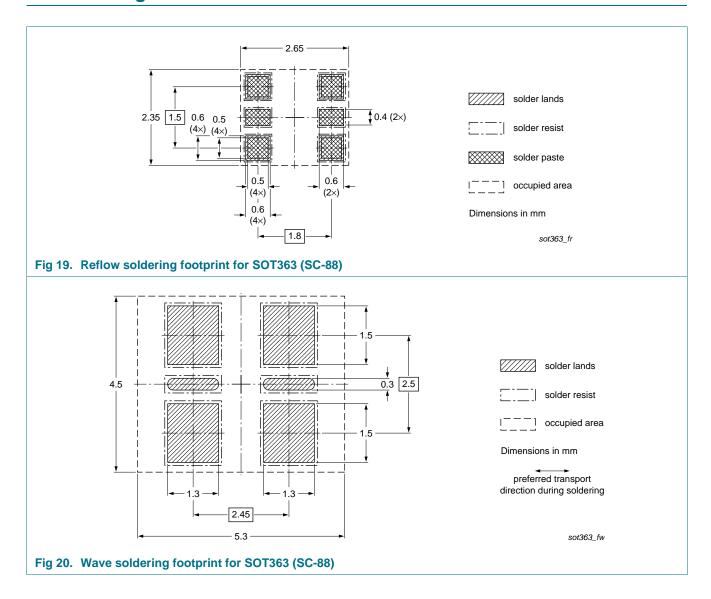
Fig 18. Package outline SOT363 (SC-88)

NX3008PBK

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## 10. Soldering



NXP Semiconductors NX3008PBKS

30 V, 200 mA dual P-channel Trench MOSFET

## 11. Revision history

### Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3008PBKS v.1	20110801	Product data sheet	-	-

## 12. Legal information

#### 12.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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## NX3008PBKS

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